Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/764,734	CHANG, AO YU		
Examiner	Art Unit		
Bena Miller	3725		

SEARCHED						
Class	Subclass	Date	Examiner			
144	333,329	9/29/2005	ввм			
	380,344					
	345,346					
	348,354					
	350-352					
	355,364					
	369					
52	730.1					
156	250,296					
	61					
428	105-107					
	114,537		6			

INTERFERENCE SEARCHED					
Class	Subclass Date		Examiner		
144	333,329, 380,344	9/29/09		Bism	
	345, 346, 354			.,-	
	350-352,				
144 369; 52 1730.1; 156 1259 296,61; 428 105-107,114,537					

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
STIC Search	9/29/2005	ввм			
EAST Search	9/29/2005	ввм			
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